# MEM6810 Engineering Systems Modeling and Simulation 工程系统建模与仿真

Theory

Analysis

Lecture 5: Input Modeling

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- The quality of outputs is no better than the quality of inputs.
  - "Garbage in, garbage out."
- "All models are wrong, but some are useful." George Box.
  - There is no "true" model for any stochastic input.
  - The best we can do is to obtain an approximation that yields reasonable and useful results.



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  - can capture the physical properties of the system;
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  - can capture the physical properties of the system;
  - can be easily tuned to the situation at hand;
  - can be efficiently generated with certain random variate generation technique.
- Input modeling is sometimes more of an art than an engineering.
  - It nearly always requires the analysts to use their judgment as well as to apply appropriate statistical tools.
  - Since there is no "true" model, it is sensible to run the simulation with several plausible input models to see if the conclusions are robust or highly sensitive to the choices.



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  - **5** If the fit is not good, select another candidate and go to Step 3, or use an empirical distribution.



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- People often have the false impression that data are readily available, but it is one of the most challenging task in solving a real problem.
- Never trust data blindly!
  - A common mistake is to simply throw data into a software and ask for a "best" fit model.
  - Always take into account under what context (e.g., time, potential influence of other factors) the data was collected.



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  - "dirty" (containing errors);
  - unexpected;
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  - stale (out of date);
  - "dirty" (containing errors);
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  - dependent.
- Sometimes the effort or cost to transform data into a usable form, or "clean" data, can be as significant as that required to obtain them.



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  - Check for autocorrelation.
  - Collect input data, not output data.
    - Example: customer arrival times and service times are input, whereas waiting times are output.



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- Do not ignore the physical characteristics of the process when selecting distributions.
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- There are literally hundreds of probability distributions that have been created; many were created with some specific physical process in mind.



► Physical Basis of Distributions

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  - empirical distribution: Often used when no theoretical distribution seems appropriate.

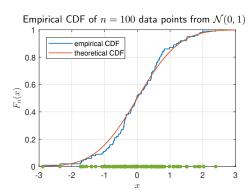
 The CDF of the empirical distribution (empirical CDF) is defined as

$$F_n(x) = \frac{\text{number of points} \le x}{n} = \frac{1}{n} \sum_{i=1}^n \mathbb{1}_{\{x_i \le x\}}.$$



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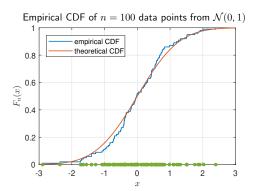
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The empirical CDF is a right-continuous step function.

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  - Weibull: Models the time to failure for components.
    - Note: the failure rate can be increasing, decreasing, or constant (reduced to exponential distribution).



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  - Erlang: Models the time that can be viewed as the sum of several exponentially distributed times.
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  - *Note*: can be shifted away from 0 by adding a constant; can cover a range different from [0,1] by multiplying by a constant.
- **triangular**: Models a process for which only the minimum, most likely, and maximum values of the distribution are known.
  - Example: only the minimum, most likely, and maximum time required to test a product are known.



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  - Useful in determining the shape of the distribution from which the data have been sampled.
- For continuous data:
  - Corresponds to the pdf of a theoretical distribution.
  - In terms of the shape, not the exact value!
- For discrete data:
  - Corresponds to the pmf of a theoretical distribution.
  - In terms of both the *shape* and *value* (if the histogram uses relative frequency).
  - If there are few data points, it could be necessary to combine adjacent cells to eliminate the ragged appearance of the histogram.





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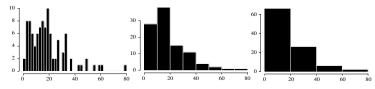


Figure: Ragged, Appropriate and Coarse Histograms (from Banks et al. (2010))





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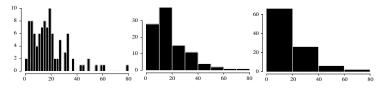


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 Choosing the number of intervals approximately equal to the square root of the sample size often works well in practice (Hines et al. 2002).

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- After a family of distributions has been selected, the next step is to determine the parameters of the distribution that can "best" fit the data.
  - Called distribution fitting, or parameter estimation.
- There are many different approaches and we discuss two simple ones:
  - method of moments (MoM)
  - maximum likelihood estimation (MLE)



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$$m_k := \frac{X_1^k + \dots + X_n^k}{n}.$$

- Suppose the considered distribution family has s unknown parameters.
  - ① Analytically compute  $\mathbb{E}[X^1], \ldots, \mathbb{E}[X^s]$ , as functions of those parameters.
    - Note: the moments of common distributions are well-known.
  - **2** Compute  $m_1, \ldots, m_s$  from the data.
  - **3** Solve  $\mathbb{E}[X^k] = m_k$ , k = 1, ..., s, for s unknown parameters.



- Example 1: Suppose  $X_1, \ldots, X_n$  are iid from  $\operatorname{Gamma}(\alpha, \lambda)$  (in shape & rate parametrization).
  - Recall:  $f(x) = \frac{\lambda^{\alpha}}{\Gamma(\alpha)} x^{\alpha-1} e^{-\lambda x}$ ,  $\mathbb{E}[X] = \alpha/\lambda$ ,  $\mathrm{Var}(X) = \alpha/\lambda^2$ .

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Estimate  $\alpha$  and  $\lambda$  using MoM.

Solution. The first two moments are

$$\mathbb{E}[X] = \alpha/\lambda = m_1,$$
  

$$\mathbb{E}[X^2] = \text{Var}(X) + (\mathbb{E}[X])^2 = (\alpha + \alpha^2)/\lambda^2 = m_2.$$

Solving two equations yields MoM estimators

$$\widehat{\alpha} = \frac{m_1^2}{m_2 - m_1^2}, \quad \widehat{\lambda} = \frac{m_1}{m_2 - m_1^2}.$$



• Example 2: Suppose  $X_1, \ldots, X_n$  are iid from  $\operatorname{Exp}(\lambda)$ . Estimate  $\lambda$  using MoM.



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Solution. The first moment is

$$\mathbb{E}[X] = 1/\lambda = m_1.$$

So the MoM estimator of  $\lambda$  is  $\widehat{\lambda} = \frac{1}{m_1} = \frac{n}{X_1 + \dots + X_n}$ .



• Example 3: Suppose  $X_1, \ldots, X_n$  are iid from  $\mathcal{N}(\mu, \sigma^2)$ . Estimate  $\mu$  and  $\sigma^2$  using MoM.



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$$\widehat{\mu} = m_1, \quad \widehat{\sigma}^2 = m_2 - m_1^2.$$



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Solving two equations yields MoM estimators

$$\widehat{\mu} = m_1, \quad \widehat{\sigma}^2 = m_2 - m_1^2.$$

• Remark:  $\widehat{\mu} = \frac{\sum_{i=1}^{n} X_i}{\widehat{x}}$ , and

$$\widehat{\sigma}^2 = \frac{X_1^2 + \dots + X_n^2}{n} - \bar{X}^2 = \frac{\sum_{i=1}^n X_i^2 - n\bar{X}^2}{n}$$

$$= \frac{\sum_{i=1}^n (X_i - \bar{X})^2}{n}. \quad \text{(why?)}$$

• Many common distributions have no more than 2 parameters: Ber(p), B(n,p), NB(r,p), Geo(p),  $Pois(\lambda)$ , Unif[a,b],  $Exp(\lambda)$ ,  $Erl(k,\lambda)$ ,  $Gamma(\alpha,\lambda)$ ,  $Beta(\alpha,\beta)$ ,  $Weibull(\alpha,\beta)$ ,  $\mathcal{N}(\mu,\sigma^2)$ ,  $t_p$ ,  $\chi_p^2$ .



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- Instead of using MoM, another convenient way to estimate the parameters is using sample mean  $\bar{X}$  and sample variance  $S^2$ :

$$\begin{split} \bar{X} &= \frac{\sum_{i=1}^{n} X_i}{n} = m_1, \\ S^2 &= \frac{\sum_{i=1}^{n} (X_i - \bar{X})^2}{n - 1} = \frac{\sum_{i=1}^{n} X_i^2 - n\bar{X}^2}{n - 1} = \frac{n}{n - 1} (m_2 - m_1^2), \end{split}$$

to solve  $\mathbb{E}[X] = \bar{X}$ , and  $\mathrm{Var}(X) = S^2$  (if necessary).



- Many common distributions have no more than 2 parameters:  $\operatorname{Ber}(p)$ ,  $\operatorname{B}(n,p)$ ,  $\operatorname{NB}(r,p)$ ,  $\operatorname{Geo}(p)$ ,  $\operatorname{Pois}(\lambda)$ ,  $\operatorname{Unif}[a,b]$ ,  $\operatorname{Exp}(\lambda)$ ,  $\operatorname{Erl}(k,\lambda)$ ,  $\operatorname{Gamma}(\alpha,\lambda)$ ,  $\operatorname{Beta}(\alpha,\beta)$ ,  $\operatorname{Weibull}(\alpha,\beta)$ ,  $\mathcal{N}(\mu,\sigma^2)$ ,  $t_p$ ,  $\chi_p^2$ .
- Instead of using MoM, another convenient way to estimate the parameters is using sample mean  $\bar{X}$  and sample variance  $S^2$ :

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• Revisit Example 1: Gamma $(\alpha, \lambda)$ . Recall: using MoM,  $\widehat{\alpha} = \frac{m_1^2}{m_2 - m_1^2}$ ,  $\widehat{\lambda} = \frac{m_1}{m_2 - m_1^2}$ .



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$$\widetilde{\lambda} = \frac{\bar{X}}{S^2}, \quad \widetilde{\alpha} = \bar{X}\widetilde{\lambda} = \frac{\bar{X}^2}{S^2}.$$



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Letting  $\mathbb{E}[X] = \bar{X}$  and  $Var(X) = S^2$ , we have

$$\widetilde{\mu}=ar{X},\quad \widetilde{\sigma}_2=S^2=rac{\sum_{i=1}^n(X_i-ar{X})^2}{n-1}.$$



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- MLE says that the parameters should take values under which the observed data are mostly likely to occur.
- Sometimes, both MoM and MLE yield the same estimator.



# Distribution Fitting

► Maximum Likelihood Estimation

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<u>Solution.</u> The pdf is  $f(x)=\lambda e^{-\lambda x}$ ,  $x\geq 0$ ,  $\lambda>0$ . So the <u>likelihood</u> of observing the above data is

$$L(\lambda) := \prod_{i=1}^{n} f(x_i) = \lambda^n e^{-\lambda(x_1 + \dots + x_n)}.$$



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We want to solve  $\lambda$  that maximizes  $L(\lambda)$ . To make it easier, we consider to maximize the *log likelihood*, which is equivalent:

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Taking its derivative w.r.t.  $\lambda$  and setting it to zero gives the solution  $\lambda^* = \frac{n}{x_1 + \dots + x_n}$ . (Check it is indeed the global maximizer!)



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Solution. The pdf is  $f(x) = \lambda e^{-\lambda x}$ , x > 0,  $\lambda > 0$ . So the likelihood of observing the above data is

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- Remarks:
  - If  $X_1, \ldots, X_n$  haven't been observed,  $\lambda^* = n/(X_1 + \cdots + X_n)$ .
  - The estimator is the same as in MoM.



<u>Solution.</u> The pdf is  $f(x)=\frac{\lambda^{\alpha}}{\Gamma(\alpha)}x^{\alpha-1}e^{-\lambda x}, \ x>0, \ \alpha>0, \lambda>0.$  So the *log likelihood* of observing the above data is

$$\ln(L(\alpha, \lambda)) = \sum_{i=1}^{n} \ln(f(x_i))$$
$$= n[\alpha \ln(\lambda) - \ln(\Gamma(\alpha))] + (\alpha - 1) \sum_{i=1}^{n} \ln(x_i) - \lambda \sum_{i=1}^{n} x_i.$$



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• For discrete distributions, replace the pdf with pmf. ( ) 并充业大学



- 1 Introduction
- 2 Data Collection
- 3 Identifying Distribution
  - ▶ Physical Basis of Distributions
  - ▶ Histogram
- 4 Distribution Fitting
  - ▶ Method of Moments
  - ► A Simple Variation of MoM
  - ► Maximum Likelihood Estimation
- Goodness of Fit
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- 6 An Illustrative Example



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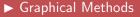
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- Try more than one plot/test before making conclusion.



► Graphical Methods

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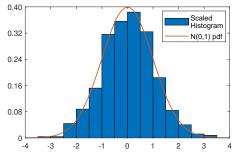


Figure: Example of Scaled Histogram vs. Fitted pdf



SHEN Haihui

• Quantile-Quantile (Q-Q) plot compares the quantiles of the data against those of the fitted distribution.



- Quantile-Quantile (Q-Q) plot compares the quantiles of the data against those of the fitted distribution.
- The q-quantile of X is that value  $\gamma$  such that  $\mathbb{P}(X \leq \gamma) = F(\gamma) = q$ , for 0 < q < 1. When F(x) has an inverse, we can write  $\gamma = F^{-1}(q)$ .
  - Median: 50% quantile.
  - In financial risk management, quantile of the profit-and-loss of a portfolio is also called Value-at-Risk (VaR).



- To make Q-Q plots, given the data  $\{x_1, \ldots, x_n\}$  and the fitted distribution with CDF F(x):
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  - If the data is indeed generated from distribution F(x), then

$$y_j \approx F^{-1} \left( \frac{j - 0.5}{n} \right)$$
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so the plot will be approximately a straight line with slop 1.



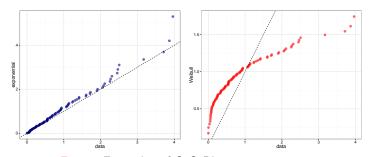


Figure: Examples of Q-Q Plot (from ZHANG Xiaowei)



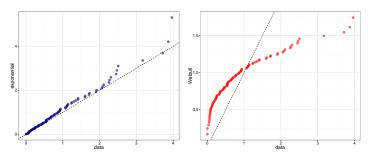


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- The observed values will never fall exactly on a straight line
- The ordered values are not independent because they are ranked.
   Hence, if one point lies above the line, it is likely that the next one will too.
- The values at the extremes have a much higher variance than those in the middle. So greater discrepancies can be acceptable at the extremes; linearity in the middle is much more important.

► Statistical Tests

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- A hypothesis test is a data-based rule to decide between the null hypothesis  $(H_0)$  and the alternative hypothesis  $(H_1)$ .
  - The basic idea is to assume  $H_0$  is true, and then check if the data provide enough evidence to conclude that  $H_0$  is not true.
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Decision Truth	reject $H_0$	fail to reject $H_0$
$H_0$ is true	type I error	correct
$H_1$ is true	correct	type II error





- A hypothesis test only directly controls the type I error.
  - A test with the same type I error probability but smaller type II error probability is better (more powerful).
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- We will reject  $H_0$  if
  - p-value is smaller than some specified  $\alpha$ , or, equivalently,
  - the computed test statistic falls in certain range (called *rejection region*), which is determined by  $\alpha$ .

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- Logic: Assume  $H_0$  is true, is it likely to observe the data at hand?
  - If the likelihood is very small (i.e., p-value is very small), then  $H_0$  is unlikely to be true (reject  $H_0$ );
  - otherwise, there is no enough evidence to reject  $H_0$  (fail to reject  $H_0$ ).



► Statistical Tests

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$$\begin{split} O_i &\coloneqq \mathbf{actual} \text{ number of data points in } [a_{i-1}, a_i), \\ E_i &\coloneqq \mathbf{expected} \text{ number of points in } [a_{i-1}, a_i) \text{ for fitted dist.} \\ &= n \times \mathbb{P}(a_{i-1} \leq X < a_i) \\ &= n \int_{a_{i-1}}^{a_i} f(x) \mathrm{d}x \quad \text{or} \quad n \sum_{a_{i-1} \leq x_i \leq a_i} p(x_j). \end{split}$$

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- **4** Reject  $H_0$  if R is too large.
  - Reason: A large value of R indicates a poor fit, whereas a small value indicates a good fit.
  - Question: How large is too large? (i.e., what is the rejection region?)





- View the test statistic R as a random variable.
  - Since we assume the collected data is one observed random sample from some unknown distribution, if we conduct the study multiple times, the values of the statistics will be different because the collected data will be different.
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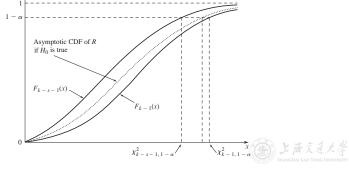
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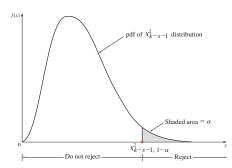
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  - p-value  $< \alpha$ , or, equivalently,
  - $r>\chi^2_{k-s-1,\,1-lpha}$ , where  $\chi^2_{k-s-1,\,1-lpha}$  is the (1-lpha)-quantile of  $\chi^2_{k-s-1}$  distribution (as shown in the following figure).



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  - It can be applied to any hypothesized distribution, which makes it widely used.
- Disadvantage of chi-square test:
  - It is valid only in an asymptotic sense (large n).
  - **Major drawback**: The validity and power of chi-square test are affected by the number and size of the chosen intervals, while there is no clear prescription for such selection.

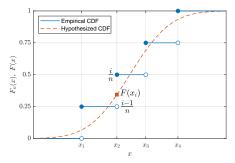


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- In the absence of a definitive guideline for choosing the intervals, it's usually recommended to make  $E_i$  equal (or approximately equal) and no less than 5, for all intervals.

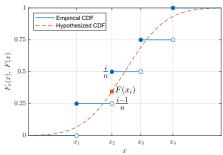


► Statistical Tests



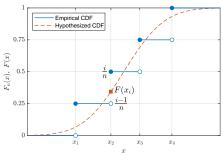






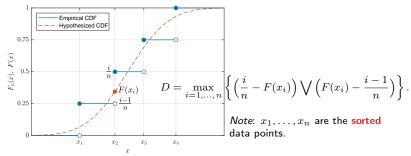
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- The procedure of K-S test:
  - $\bullet$  Compute the test statistic D.
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    - Reason: A large value of  ${\cal D}$  indicates a poor fit, whereas a small value indicates a good fit.
- For current data at hand, we have already observed the value of D, which is denoted as d. **Reject**  $H_0$  if
  - p-value =  $\mathbb{P}(D > d) < \alpha$ , or equivalently,
  - $d > d_{n,1-\alpha}$ , where  $d_{n,1-\alpha}$  is the  $(1-\alpha)$ -quantile of D.



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- If F(x) is CDF of distribution such as normal, exponential, or Weibull, and parameters are estimated via MLE (except for normal  $\sigma^2$ , which is estimated by  $S^2$ ):
  - Given  $H_0$  is true, the distribution of D depends on F(x), and it is complicated.
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### Advantage of K-S test:

- It does not require us to group the data in any way, so no information is lost and no troublesome selection is faced.
- It is valid (exactly) for any sample size, whereas chi-square test is valid only in an asymptotic sense.
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  - When applicable, its computation of p-value and rejection region is usually complicated.
- K-S test is relatively more convenient to be used in a case where the hypothesized distribution is continuous and no parameter is estimated. For example:
  - Test random number generators.
  - Test a Poisson process (more details later).





- Comments on *p*-value:
  - p-value can be viewed as a measure of fit: a large p-value tends to indicate a good fit, while a small p-value suggests a poor fit.
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- ullet Different statistical tests may give different  $p ext{-values}$ .
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  - If very little data are available, then a goodness-of-fit test is unlikely to reject any candidate distribution.
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    - $-H_0$  is virtually never exactly true, and even a tiny departure from the hypothesized distribution will be detected for large n.
  - Do not have blind faith in goodness-of-fit tests!
    - Failing to reject a candidate distribution should be taken as only one piece of evidence in favor of that choice.
    - Rejecting a candidate distribution should be taken as only one piece of evidence against the choice.



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  - Graphical methods qualitatively measure the fitting goodness, while statistical tests quantitatively measure the fitting goodness.
  - Statistical tests measure the lack of fit by summary statistics, while graphical methods show where the lack of fit occurs (body, left tail, right tail) and allow users to decide whether it is important.
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- Always combine statistical test results with graphical analysis.
- When no model fits the data satisfactorily, we may end up with the empirical distribution.





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- Many softwares do have a "best fit" option (or button).
  - It recommends the "best" distribution in its library based on summary measure like the *p*-value (and perhaps other factors such as discrete or continuous, bounded or unbounded).
- Always keep the following in mind when using such an option:
  - The software might know nothing about the physical basis of the data.
  - Automated best-fit procedures tend to choose the more flexible distributions (gamma over Erlang, Weibull over exponential).
  - But, close conformance to the data does not always lead to the most appropriate input model (overfitting).
  - The limitation of summary measure like *p*-value.
  - View the automated distribution selection as one suggestion, inspect it using graphical methods, and remember that the final choice is yours.



- All the graphical methods and statistical tests can be used to check the uniformity of a random number generator (RNG).
  - Generate a sequences of numbers (as many as you want) using the RNG.
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  - Suppose we observe an arrival process for a time interval [0, T], where T is a constant decided before we start our observation.
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  - Method 2: Test if  $\mathrm{Unif}(0,T)$  can fit the data  $\{s_1,\ldots,s_n\}$  well. (Why?)



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    - Given N(T) = n, the n arrival times  $S_1, \ldots, S_n$  have the same distribution as n independent RVs from  $\mathrm{Unif}(0,T)$  that are **sorted**.



- 1 Introduction
- 2 Data Collection
- 3 Identifying Distribution
  - ▶ Physical Basis of Distributions
  - ▶ Histogram
- 4 Distribution Fitting
  - ▶ Method of Moments
  - ► A Simple Variation of MoM
  - ► Maximum Likelihood Estimation
- Goodness of Fit
  - ► Graphical Methods
  - ► Statistical Tests
  - ▶ Remarks
- 6 An Illustrative Example



 Suppose we want to build a statistical model for the life time (i.e., time to failure) of a electronic component at 1.5 times the nominal voltage.



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#### Data Collection.

• Perform life tests on a random sample (n = 50) of electronic components and record their lifetime, in days:

79.919	3.081	0.062	1.961	5.845
3.027	6.505	0.021	0.013	0.123
6.769	59.899	1.192	34.760	5.009
18.387	0.141	43.565	24.420	0.433
144.695	2.663	17.967	0.091	9.003
0.941	0.878	3.371	2.157	7.579
0.624	5.380	3.148	7.078	23.960
0.590	1.928	0.300	0.002	0.543
7.004	31.764	1.005	1.147	0.219
3.217	14.382	1.008	2.336	4.562



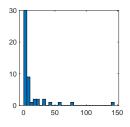
### 2 Identifying Distribution.

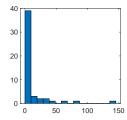
- Lifetime, although recorded to three-decimal-place accuracy, is a positive continuous variable.
- For this life time, naturally, exponential and Weibull are considered.

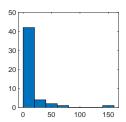


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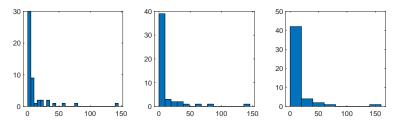






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• We decide to first try exponential distribution family  $\text{Exp}(\lambda)$ .

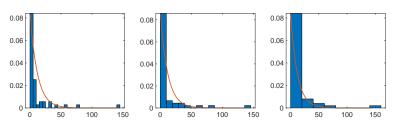


## 3 Distribution Fitting.

- Recall Example 2, MoM (or its variation) and MLE yield the same estimator for  $\lambda$ , which is  $\widehat{\lambda} = \frac{n}{X_1 + \dots + X_n}$ .
- Plug the data in, and the estimate of  $\lambda$  is 0.084.

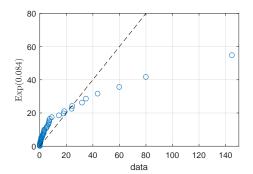


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- 4 Goodness of Fit.
  - Scaled histogram vs. pdf of Exp(0.084).





- 4 Goodness of Fit.
  - Q-Q plot.





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- 4 Goodness of Fit.
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Class Interval	Observed Frequency O <sub>i</sub>	Expected Frequency $E_i$	$\frac{(O_i - E_i)^2}{E_i}$
[0, 1.590)	19	6.25	26.01
[1.590, 3.425)	10	6.25	2.25
[3.425, 5.595)	3	6.25	0.81
[5.595, 8.252)	6	6.25	0.01
[8.252, 11.677)	1	6.25	4.41
[11.677, 16.503)	1	6.25	4.41
[16.503, 24.755)	4	6.25	0.81
[24.755, ∞)	6	6.25	0.01
	50	50	39.6



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Number of intervals is k=8. Compute test statistic  $r=\sum_{i=1}^k \frac{(O_i-E_i)^2}{E_i}=39.6$ .



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Number of intervals is k = 8.

Compute test statistic 
$$r = \sum_{i=1}^k \frac{(O_i - E_i)^2}{E_i} = 39.6$$
.

Note that  $R \sim \chi^2_{k-s-1}$  distribution =  $\chi^2_6$  distribution.

So, *p*-value = 
$$\mathbb{P}(R \ge r) = \mathbb{P}(R \ge 39.6) = 5 \times 10^{-7}$$
.



- 4 Goodness of Fit.
  - Chi-square test  $(H_0$ : The data come from Exp(0.084)). Number of estimated parameters is s = 1.

Choose intervals (make  $E_i$  equal).

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Note that 
$$R \sim \chi^2_{k-s-1}$$
 distribution =  $\chi^2_6$  distribution.

So, *p*-value = 
$$\mathbb{P}(R > r) = \mathbb{P}(R > 39.6) = 5 \times 10^{-7}$$
.

Hence, at almost any practical level of significance, e.g.,  $\alpha = 0.05$ ,  $\alpha = 0.01$ , we will reject  $H_0$ .

